

**Notice of References Cited**

Application/Control No.

09/675,427

Applicant(s)/Patent Under  
Reexamination  
SAXENA ET AL.

Examiner

Morella I Rosales-Hanner

Art Unit

2128

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,356,861	03-2002	Singhal et al.	703/2
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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